



**International
Standard**

ISO 5618-2

**Fine ceramics (advanced ceramics,
advanced technical ceramics) —
Test method for GaN crystal surface
defects —**

**Part 2:
Method for determining etch pit
density**

*Céramiques techniques — Méthode d'essai pour les défauts de
surface des cristaux de GaN —*

Partie 2: Méthode de détermination de la densité des piqûres

**First edition
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